## Notice of References Cited Application/Control No. 10/752,431 Examiner David C. Reese Applicant(s)/Patent Under Reexamination BAER ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,666,638	12-2003	Craven, Arnold	411/413
	В	US-6,254,327	07-2001	Chen, Chun-Chin	411/411
	С	US-5,516,248	05-1996	DeHaitre, Lon	411/387.2
	D	US-2003/0026675	02-2003	McGovern et al.	411/412
	Е	US-5,217,339	06-1993	O'Connor et al.	411/531
	F	US-4,959,938	10-1990	De Caro, Charles J.	52/410
	G	US-4,808,051	02-1989	Gietl, Hans	411/378
	Н	US-5,044,855	09-1991	Fukubayashi, Kenji	411/386
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	$^{\wedge}$					
	V						
	w						
	×						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.